December 2001

FDR842P

FAIRCHILD SEMICONDUCTOR®

P-Channel 1.8V Specified PowerTrench[®] MOSFET

General Description

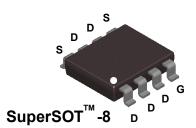
This P-Channel –1.8V specified MOSFET uses Fairchild's advanced low voltage PowerTrench process. It has been optimized for battery power management applications.

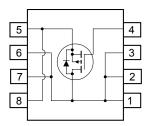
Applications

- Power management
- Load switch
- Battery protection

Features

- -11 A, -12 V $R_{DS(ON)}$ = 9 m Ω @ V_{GS} = -4.5 V $R_{DS(ON)}$ = 12 m Ω @ V_{GS} = -2.5 V $R_{DS(ON)}$ = 16 m Ω @ V_{GS} = -1.8 V
- Fast switching speed
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-12	V
V _{GSS}	Gate-Source Voltage		± 8	V
I _D	Drain Current – Continuous	(Note 1a)	–11	А
	– Pulsed		-50	
PD	Power Dissipation for Single Operation	(Note 1a)	1.8	W
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{STG}	Operating and Storage Junction Tempera	ture Range	-55 to +150	°C

Thermal Characteristics

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	70	°C/W
$R_{ ext{ ext{ ext{ ext{ ext{ ext{ ext{ ext$	Thermal Resistance, Junction-to-Case	(Note 1)	20	°C/W

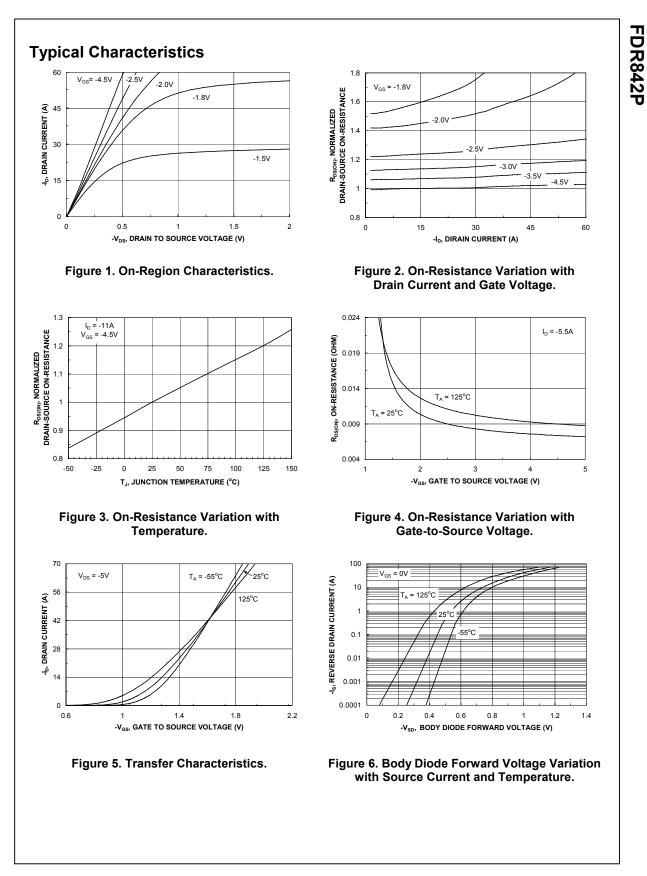
Package Marking and Ordering Information

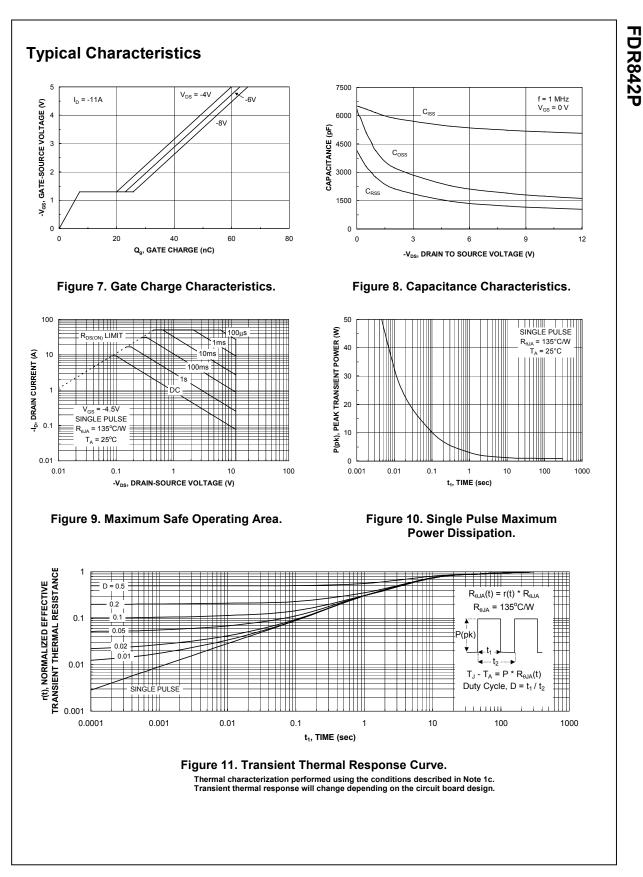
Device Marking	Device	Reel Size	Tape width	Quantity
FDR842P	FDR842P	13"	12mm	2500 units

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FDR842P

	Test Conditions	Min	Тур	Max	Units
cteristics			<u> </u>		
Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = -250 \mu A$	-12			V
Breakdown Voltage Temperature Coefficient	I_D = –250 µA, Referenced to 25°C		-4.4		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = -10 V$, $V_{GS} = 0 V$			-1	μA
Gate–Body Leakage, Forward	$V_{GS} = 8 V, \qquad V_{DS} = 0 V$			100	nA
Gate–Body Leakage, Reverse	$V_{GS} = -8 V, \qquad V_{DS} = 0 V$			-100	nA
Cteristics (Note 2)					
Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	-0.4	-0.5	-1.5	V
Gate Threshold Voltage Temperature Coefficient	I_D = –250 µA, Referenced to 25°C		2.7		mV/°C
Static Drain–Source On–Resistance	$ \begin{array}{l} V_{GS} = -4.5 \ V, I_D = -11 \ A \\ V_{GS} = -2.5 \ V, I_D = -9.5 \ A \\ V_{GS} = -1.8 \ V, I_D = -7.5 \ A \\ V_{GS} = -4.5 \ V, \ I_D = -11 \ A, \ T_J = 125^\circ C \end{array} $		7 9 12 9	9 12 16 12	mΩ
On-State Drain Current	$V_{GS} = -4.5 V$, $V_{DS} = -5 V$	-50	T		Α
Forward Transconductance	$V_{DS} = -5 V$, $I_D = -11 A$		56		S
Characteristics					
Input Capacitance	$V_{DS} = -6 V$, $V_{GS} = 0 V$,		5350		pF
Output Capacitance	f = 1.0 MHz		2135		pF
Reverse Transfer Capacitance			1386		pF
Characteristics (Note 2)					
Turn–On Delay Time	$V_{DD} = -6 V$, $I_D = -1 A$,		17	30	ns
Turn–On Rise Time	$V_{GS} = -4.5$ V, $R_{GEN} = 6 \Omega$		20	35	ns
Turn–Off Delay Time			201	322	ns
Turn–Off Fall Time			161	258	ns
Total Gate Charge	$V_{DS} = -6 V$, $I_D = -11 A$,		57	80	nC
Gate–Source Charge	$V_{GS} = -4.5 V$		7		nC
Gate–Drain Charge			16		nC
urce Diode Characteristics	and Maximum Ratings	•			
				-1.5	Α
Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = -1.5 A$ (Note 2)		-0.6	-1.2	V
	Coefficient Zero Gate Voltage Drain Current Gate–Body Leakage, Forward Gate–Body Leakage, Reverse Cteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain–Source On–Resistance On–State Drain Current Forward Transconductance Characteristics Input Capacitance Output Capacitance Output Capacitance Reverse Transfer Capacitance Characteristics (Note 2) Turn–On Delay Time Turn–On Rise Time Turn–Off Delay Time Turn–Off Fall Time Total Gate Charge Gate–Source Charge Gate–Drain Charge Urce Diode Characteristics Maximum Continuous Drain–Source Drain–Source Diode Forward Voltage	CoefficientVois = -10 V, Vois = 0 VZero Gate Voltage Drain Current $V_{GS} = -8 V, V_{DS} = 0 V$ Gate-Body Leakage, Forward $V_{GS} = 8 V, V_{DS} = 0 V$ Gate-Body Leakage, Reverse $V_{GS} = -8 V, V_{DS} = 0 V$ Gate Threshold Voltage $V_{DS} = -8 V, V_{DS} = 0 V$ Gate Threshold Voltage $V_{DS} = -8 V, V_{DS} = 0 V$ Gate Threshold Voltage $I_D = -250 \mu A$, Referenced to 25°CStatic Drain-Source $V_{GS} = -4.5 V, I_D = -11 A$ On-Resistance $V_{GS} = -4.5 V, I_D = -9.5 A$ $V_{GS} = -1.8 V, I_D = -7.5 A$ $V_{GS} = -4.5 V, I_D = -7.5 A$ $V_{GS} = -4.5 V, I_D = -11 A, T_J = 125°C$ On-State Drain Current $V_{GS} = -5 V, I_D = -11 A$ Characteristics Input Capacitance $V_{DS} = -5 V, I_D = -11 A$ Characteristics Input Capacitance P	CoefficientVDS -10 V, $V_{GS} = 0$ VZero Gate Voltage Drain Current $V_{DS} = -10$ V, $V_{GS} = 0$ VGate-Body Leakage, Forward $V_{GS} = 8$ V, $V_{DS} = 0$ VGate-Body Leakage, Reverse $V_{GS} = -8$ V, $V_{DS} = 0$ VCteristics(Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 \ \mu$ A, Referenced to 25° CStatic Drain-Source $V_{GS} = -4.5$ V, $I_D = -11$ AOn-Resistance $V_{GS} = -4.5$ V, $I_D = -11$ A $V_{GS} = -4.5$ V, $I_D = -9.5$ A $V_{GS} = -4.5$ V, $I_D = -9.5$ A $V_{GS} = -4.5$ V, $I_D = -7.5$ A $V_{GS} = -4.5$ V, $I_D = -7.5$ A $V_{GS} = -4.5$ V, $I_D = -11$ A, $T_J = 125^{\circ}$ COn-State Drain Current $V_{GS} = -4.5$ V, $V_{DS} = -5$ V -50 Forward Transconductance $V_{DS} = -5$ V, $I_D = -11$ ACharacteristicsInput Capacitance $V_{DS} = -6$ V, $V_{GS} = 0$ V, $f = 1.0$ MHzReverse Transfer Capacitance $f = 1.0$ MHzTurm-On Delay TimeTurm-On Rise TimeTurm-Off Delay TimeTurm-Off Fall TimeTotal Gate Charge $V_{CS} = -6$ V, $I_D = -11$ A,Gate-Source Charge $V_{GS} = -4.5$ VGate-Source Diode Characteristics and Maximum RatingsMaximum Continuous Drain-Source Diode Forward CurrentDrain-Source Diode Forward $V_{CS} = 0$ V, $I_S = -1.5$ A (Note 2)	Coefficient-4.4Zero Gate Voltage Drain Current $V_{DS} = -10 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage, Forward $V_{GS} = 8 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -8 \text{ V}$, $V_{DS} = 0 \text{ V}$ Cteristics(Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 \mu \text{ A}$ Gate Threshold Voltage $I_D = -250 \mu \text{ A}$, Referenced to 25° C 2.7Static Drain-Source $V_{GS} = -4.5 \text{ V}$, $I_D = -11 \text{ A}$ $V_{GS} = -2.5 \text{ V}$, $I_D = -7.5 \text{ A}$ $V_{GS} = -2.5 \text{ V}$, $I_D = -9.5 \text{ A}$ $V_{GS} = -4.5 \text{ V}$, $I_D = -7.5 \text{ A}$ $V_{GS} = -4.5 \text{ V}$, $I_D = -7.5 \text{ A}$ $V_{GS} = -4.5 \text{ V}$, $I_D = -11 \text{ A}$, $T_J = 125^{\circ} \text{ C}$ 9 On-State Drain Current $V_{GS} = -4.5 \text{ V}$, $V_{DS} = -5 \text{ V}$ -50 Forward Transconductance $V_{DS} = -6 \text{ V}$, $V_{GS} = 0 \text{ V}$, $Static Drain-Capacitance$ $P_{DD} = -6 \text{ V}$, $V_{GS} = 0 \text{ V}$, $Static Drain-Capacitance$ $P_{DD} = -6 \text{ V}$, $V_{GS} = 0 \text{ V}$, $State Drain CurrentV_{CS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega201Turn-On Blay TimeTurn-On Fise TimeTurn-Onf Fall TimeTotal Gate ChargeV_{CS} = -4.5 \text{ V}Reverse Transfer CapacitanceTotal Gate ChargeV_{CS} = -6 \text{ V}, V_{CS} = 6 \Omega201Turn-Onf Fall TimeTotal Gate ChargeReverse Transfer CapeReverse Transfer Cape<$	CoefficientThe second sec





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